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(12) **United States Design Patent**  
**Noda et al.**

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(54) **ELECTRON MICROSCOPE**

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(\*\*) Term: **14 Years**

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(52) **U.S. Cl.** ..... **D16/131**

(58) **Field of Classification Search** ..... D16/131,  
D16/130; D24/186, 216, 232; D10/81; 250/307,  
250/310, 311, 397, 440.11; 359/383, 384,  
359/385, 389, 390, 368, 370, 371, 372, 363,  
359/388

See application file for complete search history.

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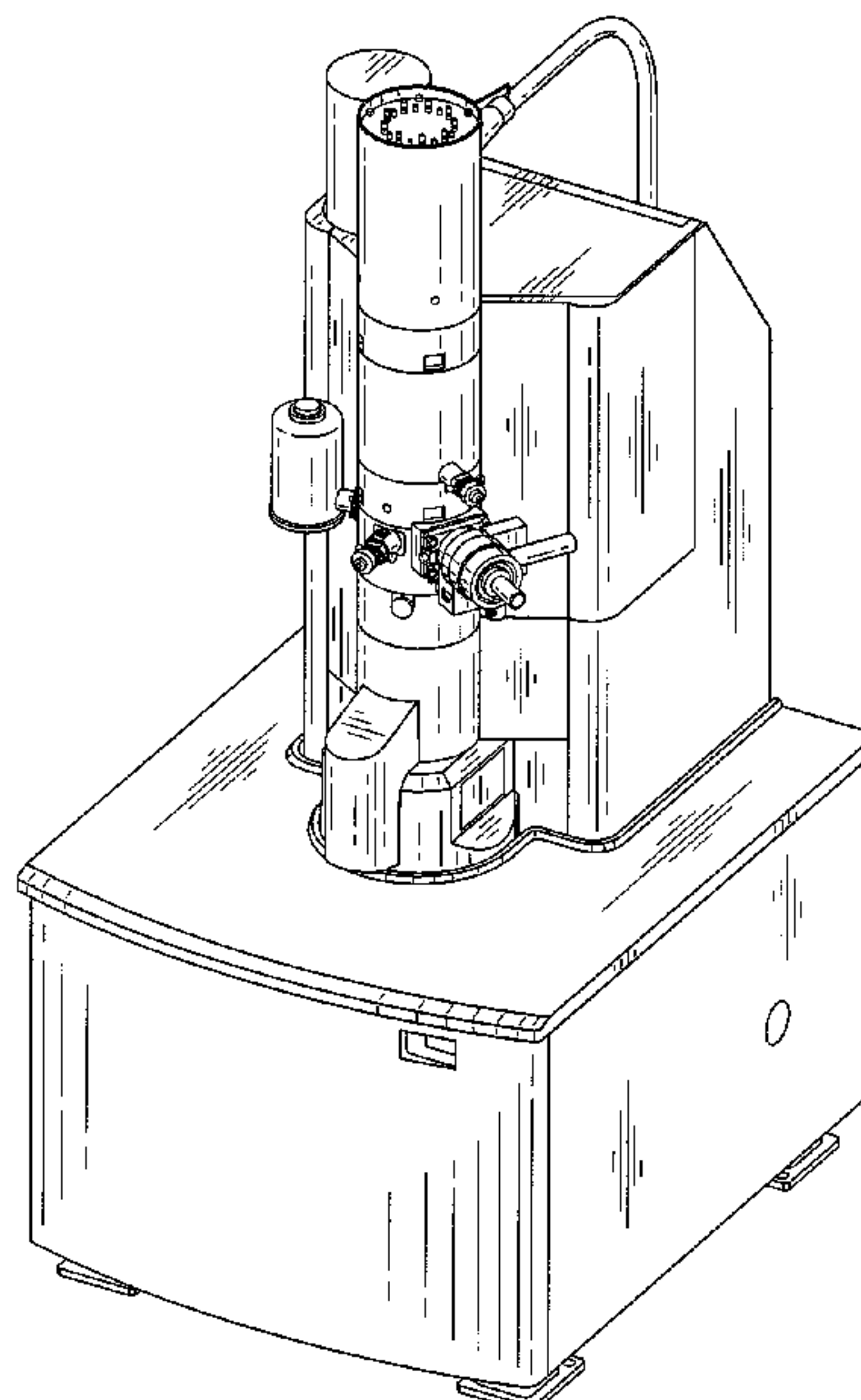
(57) **CLAIM**

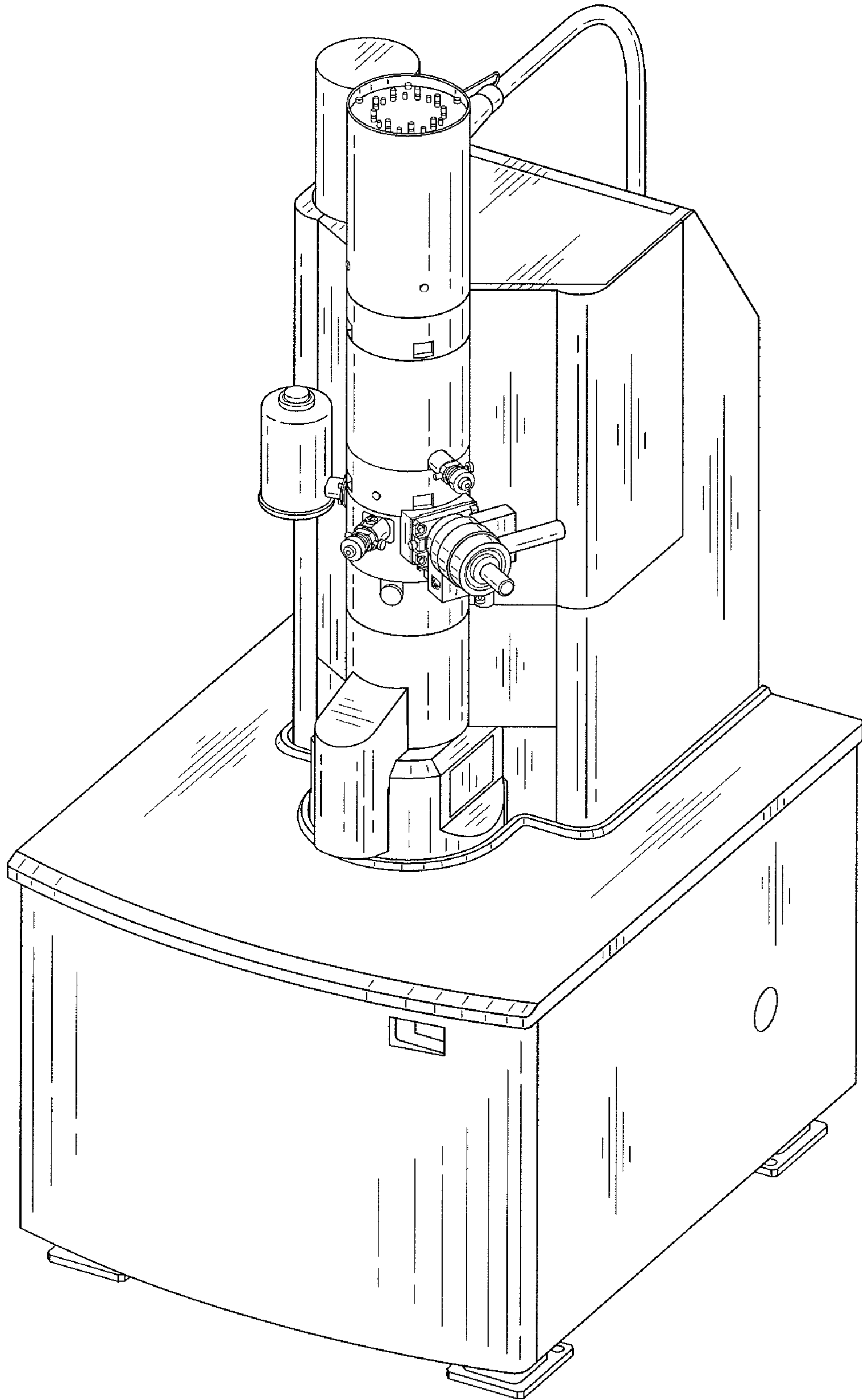
We claim the ornamental design for an electron microscope, as shown and described.

**DESCRIPTION**

FIG. 1 is a front, top and right side perspective view of an electron microscope showing our new design;  
FIG. 2 is a front elevational view thereof;  
FIG. 3 is a rear elevational view thereof;  
FIG. 4 is a top plan view thereof;  
FIG. 5 is a bottom plan view thereof;  
FIG. 6 is a left side elevational view thereof; and,  
FIG. 7 is a right side elevational view thereof.  
The broken lines shown are for illustrative purposes only and form no part of the claimed design.

**1 Claim, 7 Drawing Sheets**





**FIG. 1**

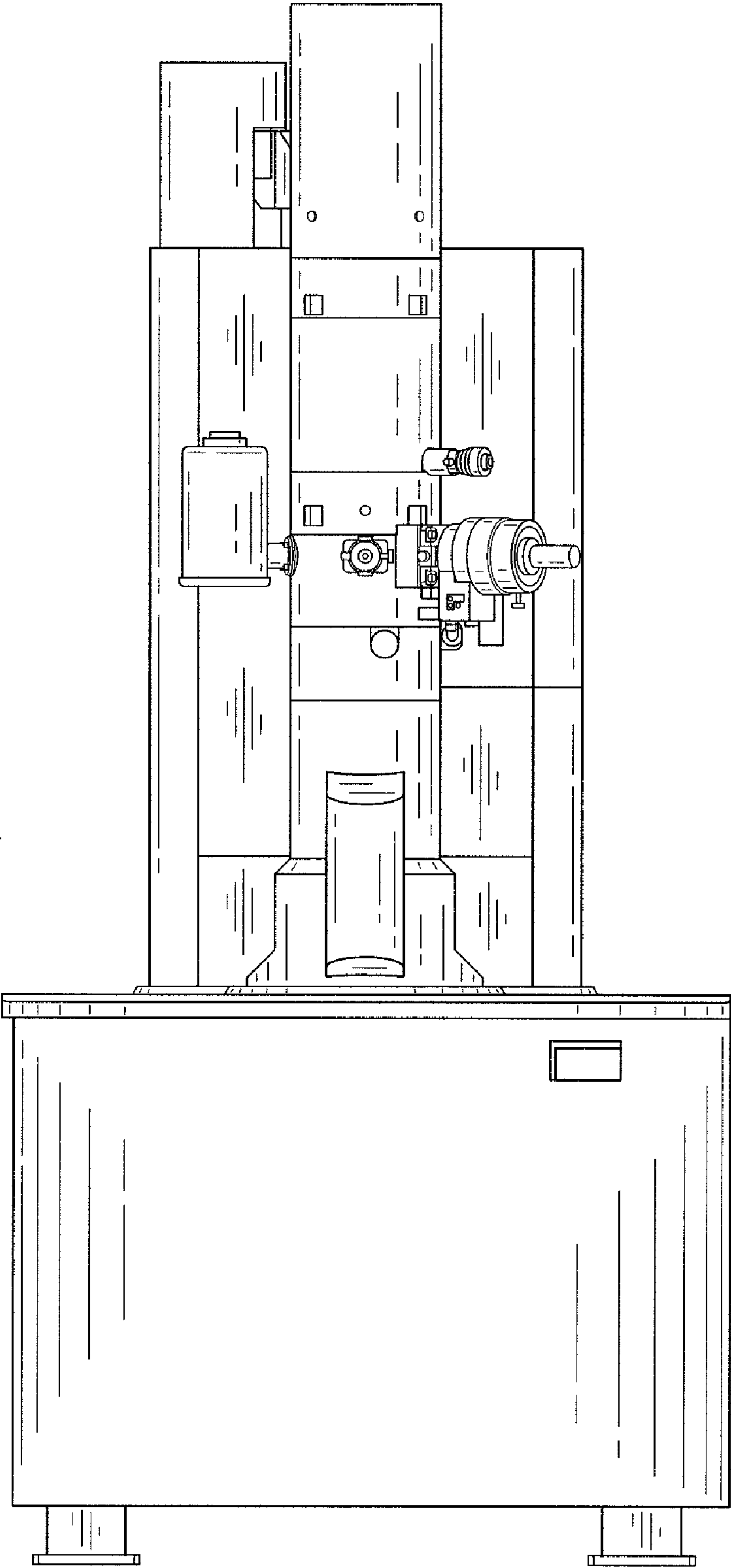


FIG. 2

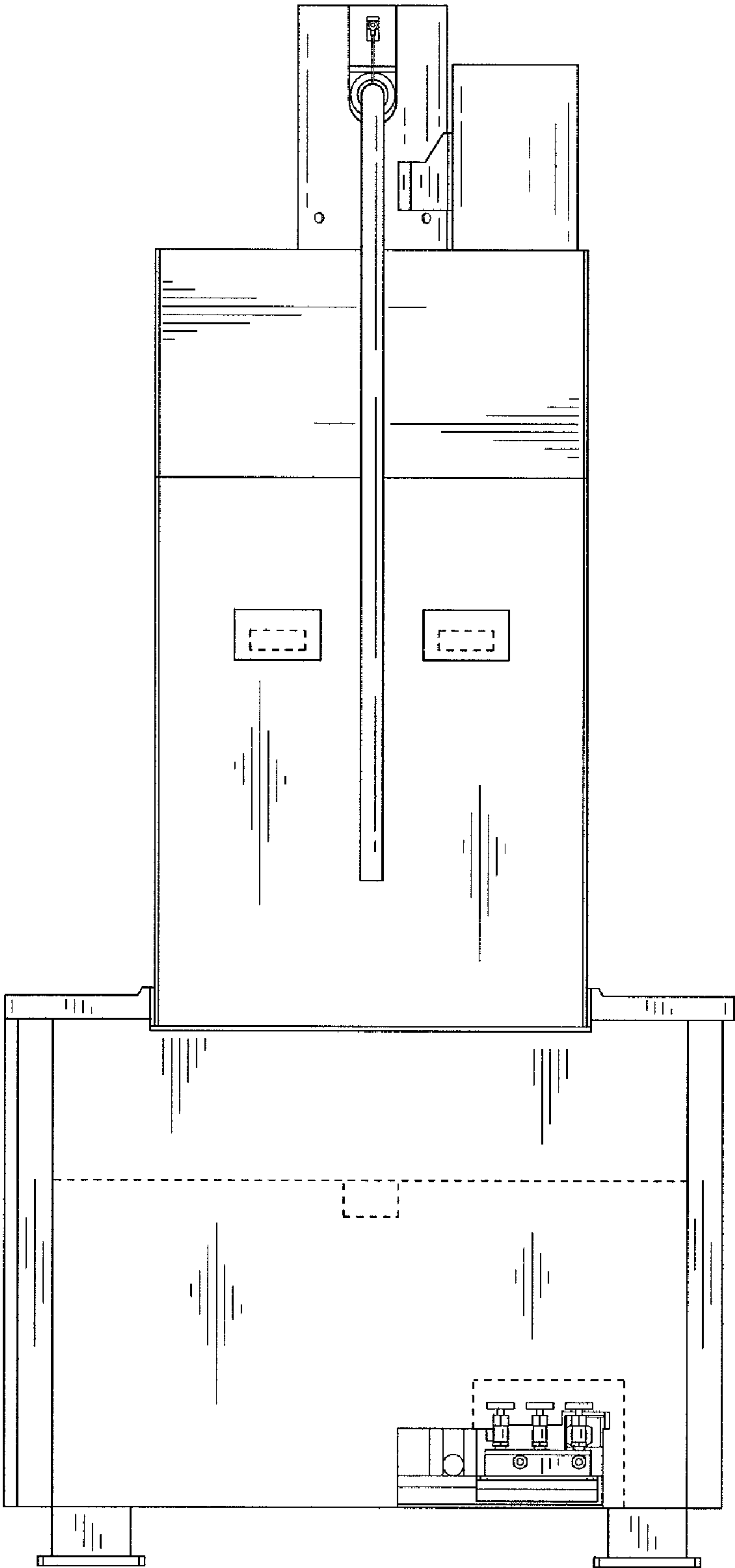
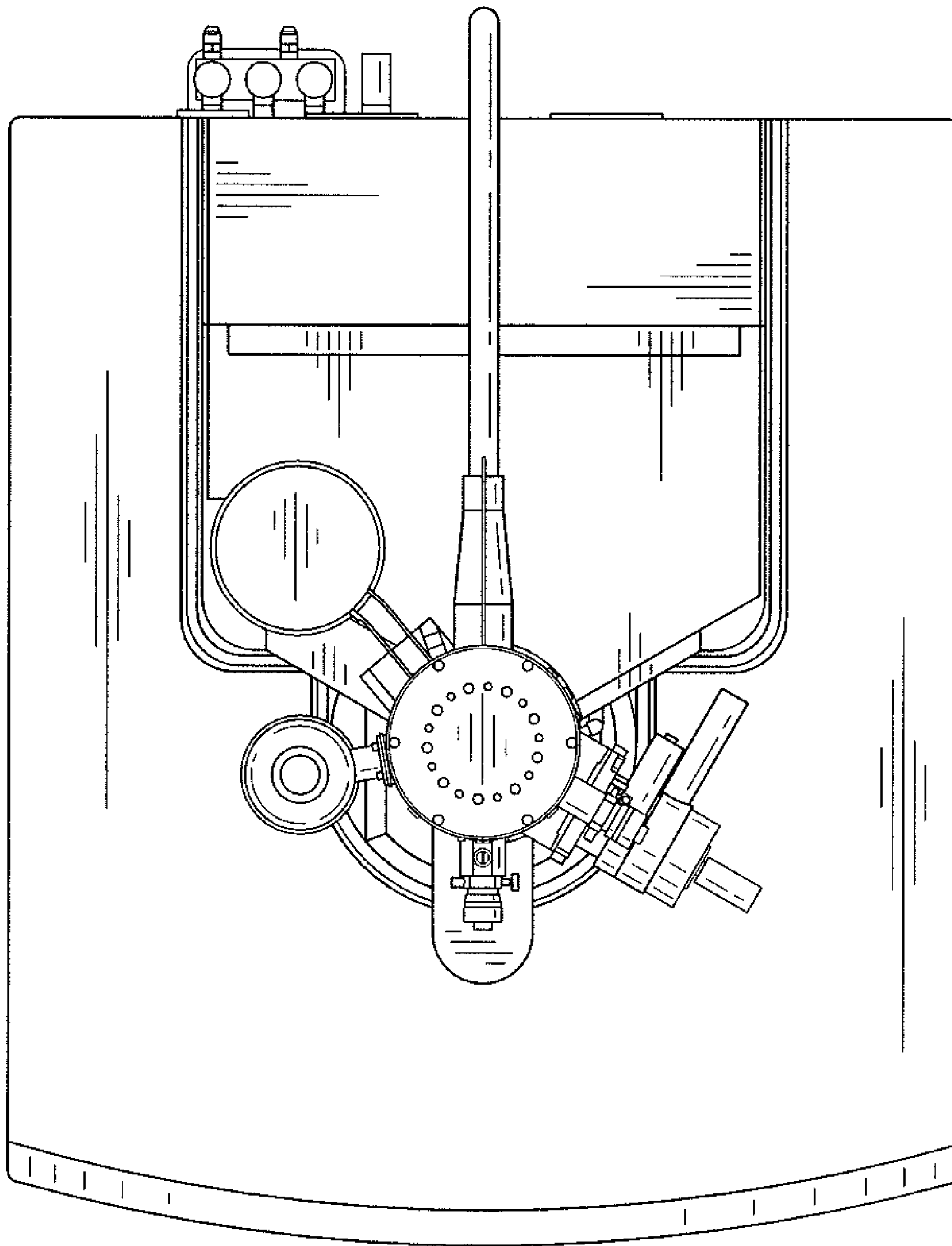
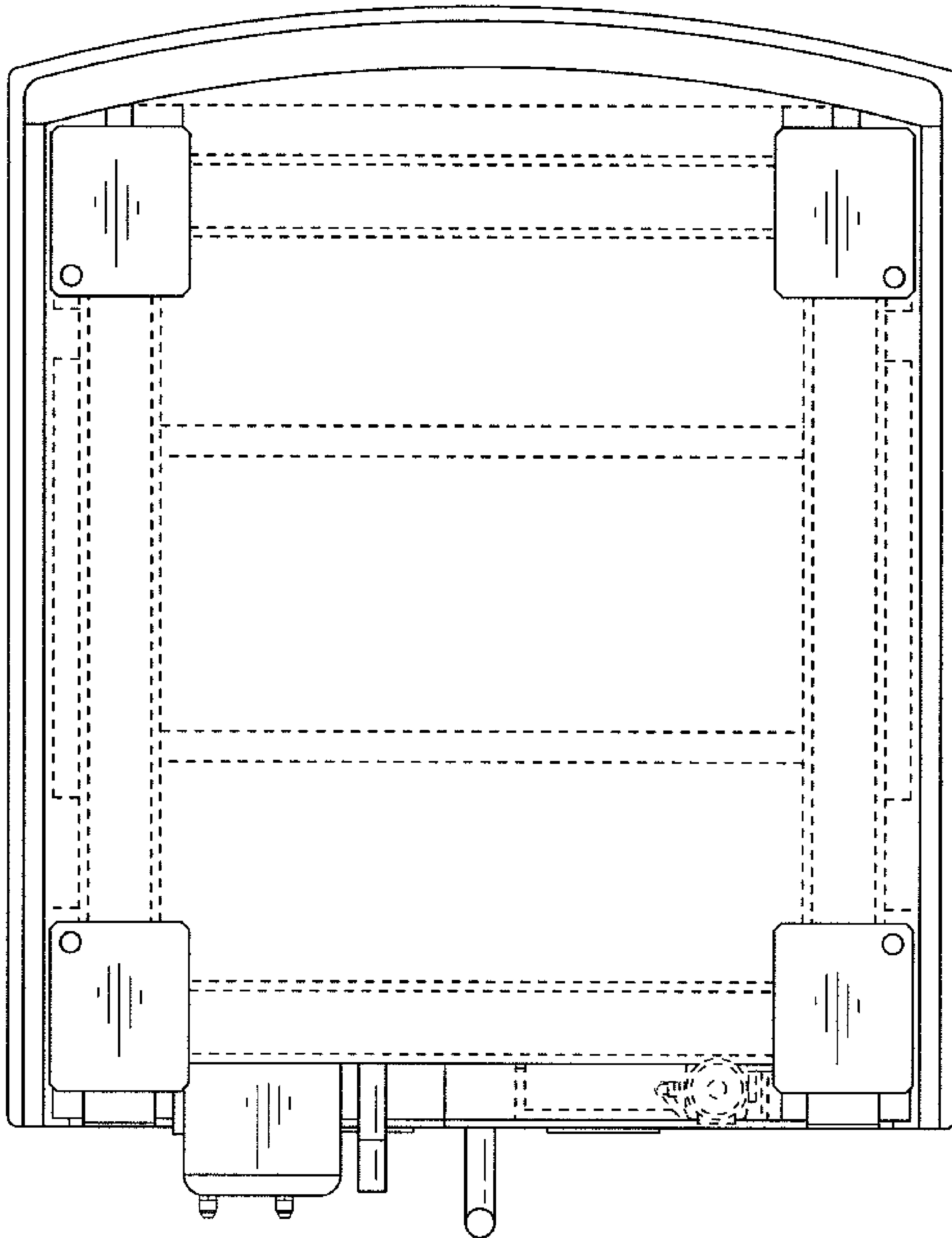


FIG. 3



**FIG. 4**



**FIG. 5**

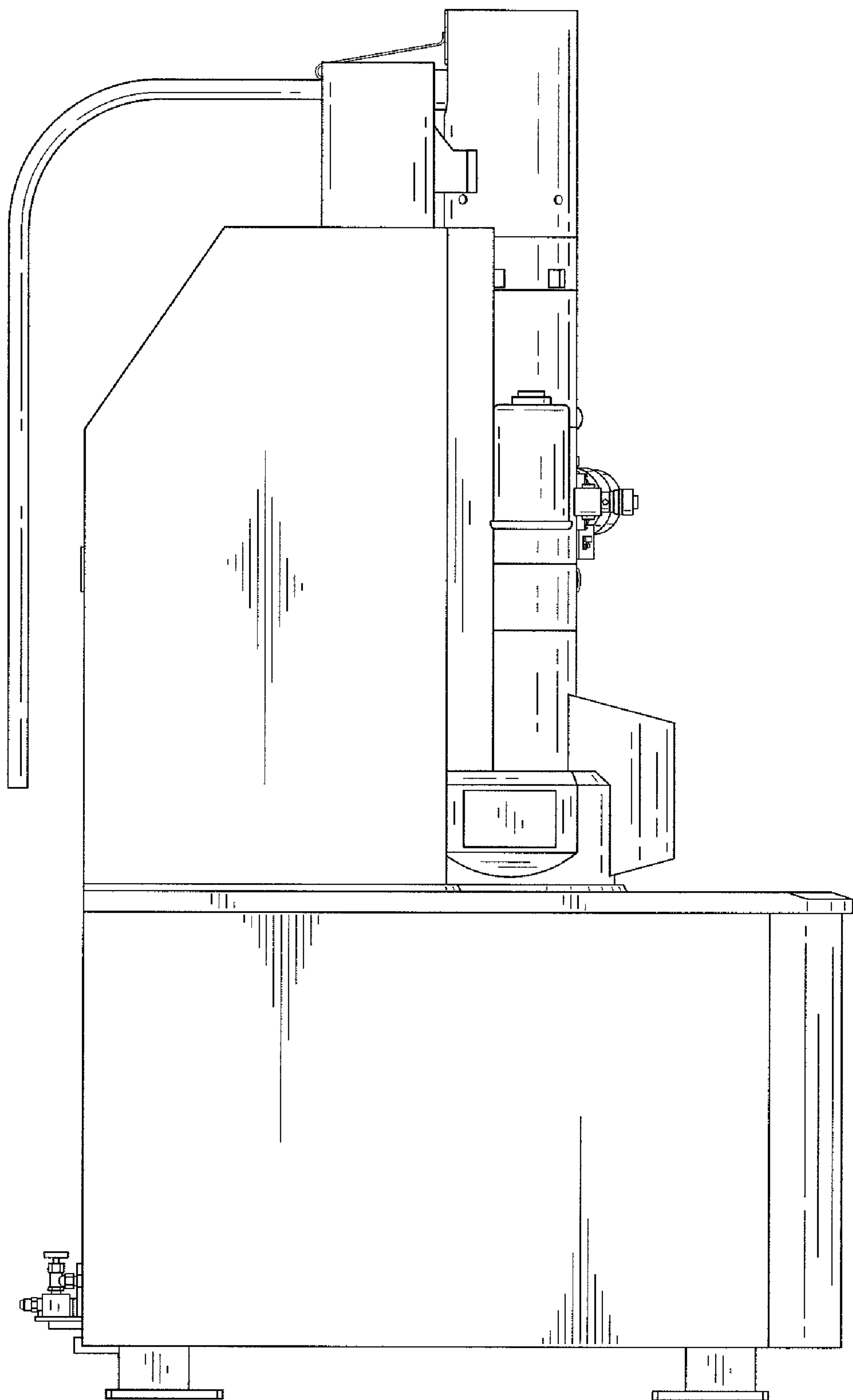


FIG. 6

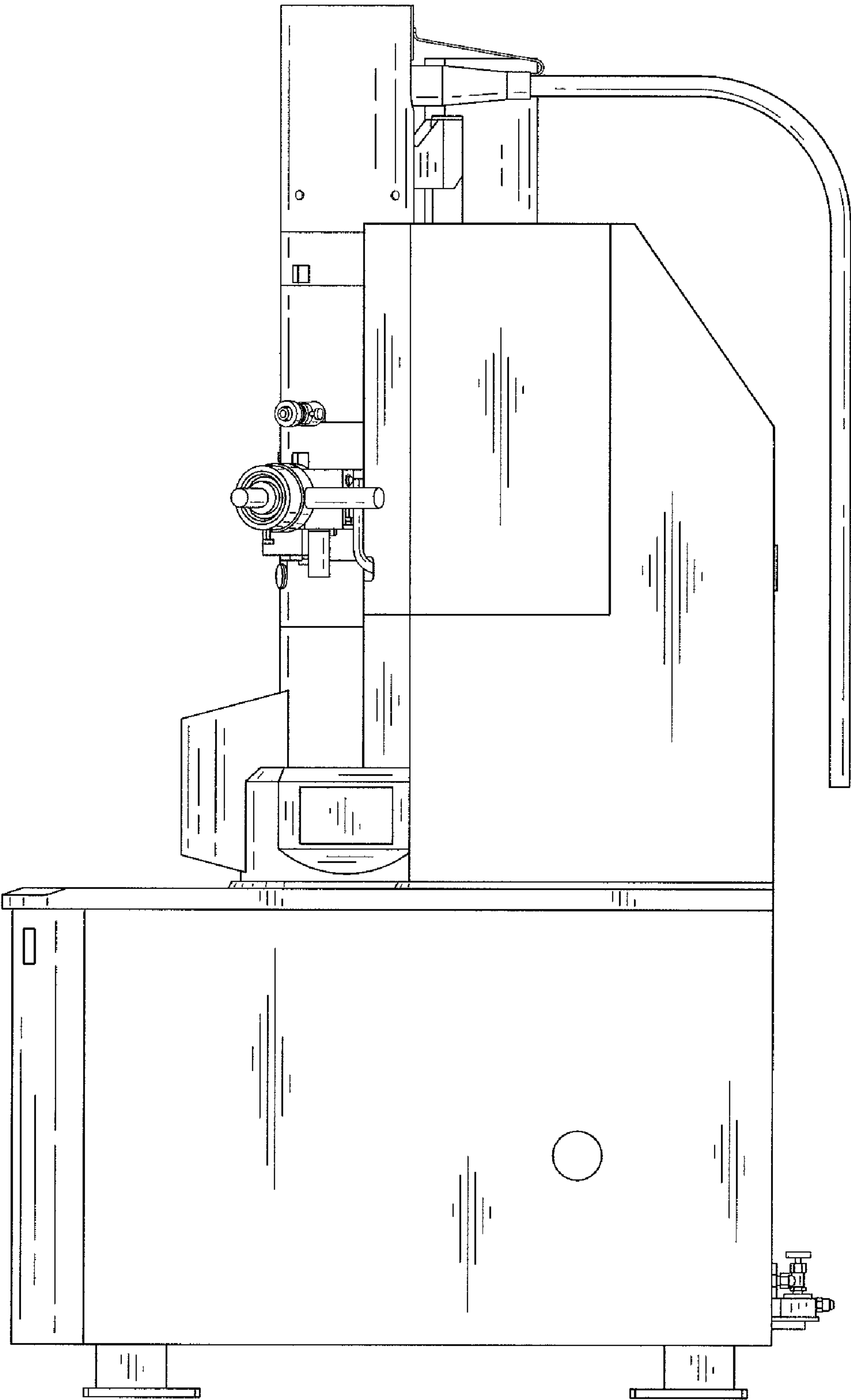


FIG. 7